

Method and arrangement for imaging and measuring microscopic three-dimensional structures

Abstract of Disclosure

The present invention concerns a method and an arrangement for imaging and measuring microscopic three-dimensional structures. In them, a data set is depicted in three-dimensional form on a display (27) associated with the microscope. At least one arbitrary section position and an arbitrary rotation angle are defined by the user. Rotation of the three-dimensional depiction on the display (27) is performed until a structure contained in the three-dimensional form reproduces on the display (27) a depiction that appears suitable to the user. The corresponding analytical operations are then performed on the structure.

Figures

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